

<b>Notice of References Cited</b>	Application/Control No. 10/769,813	Applicant(s)/Patent Under Reexamination LEE, JONG HYEOK	
	Examiner TAN X. DINH	Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,859,425 b2	02-2005	Maegawa et al.	369/47.3
*	B	US-6,594,210 b2	07-2003	Kumagai, Eiji	369/47.17
*	C	US-6,560,170 b2	05-2003	Hirose, Hirokazu	369/30.04
*	D	US-2004/0130991 a1	07-2004	Tawaragi, Yuji	369/053.22
*	E	US-2004/0218497 a1	11-2004	Choi et al.	369/053.23
*	F	US-2001/0043515	11-2001	Ueki, Yasuhiro	369/30.1
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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